

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/743,147	<b>Applicant(s)/Patent under Reexamination</b> CHEN, CHIH-YUAN
<b>Examiner</b> Joseph Haley	<b>Art Unit</b> 2627	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner